

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/605,058	DELINE, JONATHAN	
Examiner Khai M. Nguyen		Art Unit 2617		Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,223,029 B1	04-2001	Stenman et al.	455/420
*	B	US-2003/0003907 A1	01-2003	Lai et al.	455/425
C	US-				
D	US-				
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H	US-				
I	US-				
J	US-				
K	US-				
L	US-				
M	US-				

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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